WHAT IS CLAIMED IS:

1	1.	A solid-state device comprising:	
2		a terminal having a plurality of fingers; and	
3		wherein said fingers are arranged so that the device is heat transfer	
4	balanced.		
1	2.	The device of Claim 1, wherein said fingers are arranged in a row and	
2	spaced non-uniformly in the row.		
1	3.	The device of Claim 1, wherein each said finger is associated with a	
2	corresponding one of a plurality of sub-cells, wherein said sub-cells are arranged in a rov		
3	and spaced non-uniformly.		
1	4.	The device of Claim 3, wherein each said sub-cell includes one finger.	
1	5.	The device of Claim 3, wherein each said sub-cell is associated with one	
2	of a plurality of rows of sub-cells.		
1	6.	The device of Claim 3, wherein the device has a terminal area defining	
2	opposed edges, and wherein adjacent ones of said sub-cells are spaced a greater distance		
3	at or near a center of the device than at or near the opposed edges.		
1	7.	The device of Claim 3, wherein a number of fingers in a sub-cell at or near	
2	a center of th	e device is less than a number of fingers in a sub-cell at or near an edge of a	
3	device.		
1	8.	The device of Claim 7, wherein the device is an HBT.	

The device of claim 8, wherein the device is a SiGe HBT.

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1	10. The device of Claim 7, wherein the device defines a terminal region an	ıd		
2	the terminal region is sized for a high power application.			
1	11. The device of Claim 1, wherein each finger is biased for its maximum			
2	2 current density during operation.			
1	12. The device of Claim 1, wherein the device defines a layout, and the lay	out/		
2	is a ballasting resistors-free layout.			
1	13. The device of Claim 1, wherein said fingers are emitter fingers.			
1	14. The device of Claim 1, wherein said fingers are arranged so that a peak	(
2	oscillation frequency, fmax, associated with the device is generally independent of the			
3	number of fingers.			
1	15. The device of Claim 1, wherein each said finger is associated with a			
2	corresponding one of a plurality of sub-cells, and wherein said sub-cells are spaced so			
3	that at least one of consecutive adjacent pairs of said sub-cells are spaced differently.			
1	16. A solid-state device comprising:			
2	a terminal having a plurality of fingers;			
3	wherein said fingers are arranged so that a peak oscillation frequency,	f _{max}		
4	associated with the device is generally independent of the number of said fingers.			
1	17. The device of Claim 16, wherein said fingers are arranged in a row and	i		
2	spaced non-uniformly in the row.			
1	18. The device of Claim 16, wherein each said finger is associated with a			
2	corresponding one of a plurality of sub-cells, wherein said sub-cells are arranged in a ro			
3	and spaced non-uniformly.			

1	19.	The device of Claim 18, wherein said sub-cells are arranged in a plurality	
2	of non-uniformly spaced rows.		
1	20.	The device of Claim 18, wherein said sub-cells each includes one finger	
1	21.	The device of Claim 17, wherein the device has a terminal area defining	
2	opposed edges, and wherein adjacent ones of said sub-cells are spaced a greater distance		
3	at or near a center of the device than at or near the opposed edges.		
1	22.	The device of Claim 16, wherein each finger is biased for its maximum	
2	current density.		
1	23.	The device of Claim 16, wherein the device is an HBT, and said fingers	
2	are emitter fingers.		
1	24.	A method of producing a high power solid-state device comprising:	
2		providing a substrate for supporting a terminal having a plurality of	
3	fingers; and		
4		arranging the fingers in a plurality of sub-cells defining at least one row so	
5	that the device is heat transfer balanced.		
1	25.	The method of Claim 24, wherein said sub-cells are arranged so that	
2	consecutive adjacent pairs of the sub-cells in the at least one row are spaced differently.		
1 2	26.	The method of Claim24, wherein the at least one row includes a plurality	
1	27.	The method of Claim 26, wherein the sub-cells between the plurality of	

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rows are spaced non-uniformly.

The method of Claim 24, further comprising determining a number of the 1 28. sub-cells and spacings between the sub-cells using a thermal simulation program. 2 The method of Claim 28, wherein the thermal simulation program uses 29. 1 finite element analysis. 2 The method of Claim 24, wherein the device is one of an HBT and a FET. 1 30. The method of Claim 24, wherein the device defines a layout that is 1 31. 2 ballasting resistors-free. A method of heat transfer balancing a solid-state device, the method 1 32. comprising: 2 arranging a plurality of fingers of a terminal of the device so that a 3 junction temperature across the device in operation is generally uniform without using 4 5 ballasting resistors. The method of Claim 32, wherein each finger is biased for its maximum 1 33. 2 current density. The method of Claim 33, wherein the device is an HBT, and the terminal is 1

an emitter terminal.

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